

Sample Memo Report

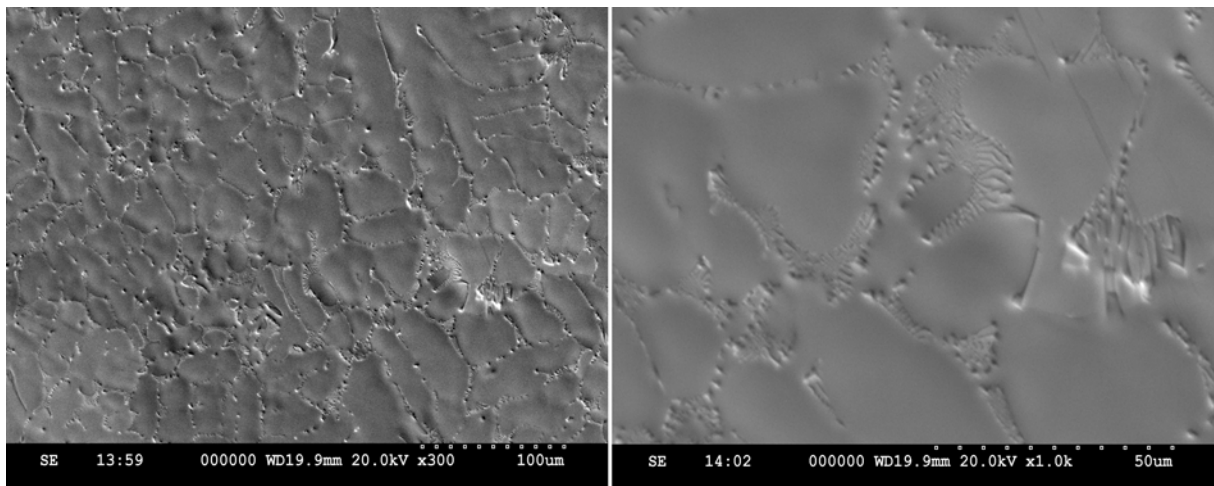
To: Torild Krogstad, Pål Ulseth

September 6, 2007

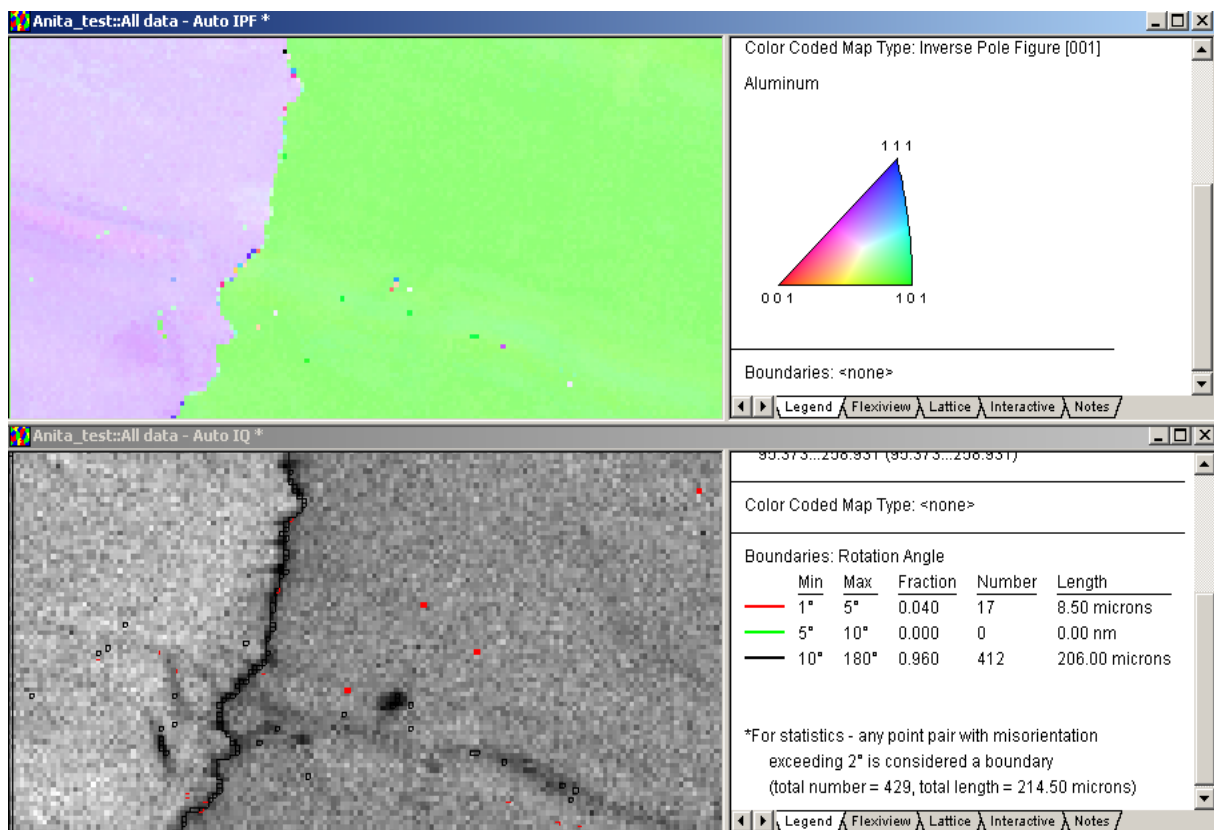
From: Yingda Yu

Subject: EBSD sample preparation test

The present treatment condition is quite suitable for EBSD sample preparation, as shown in the below SEM macrographs at x30 and x1000 magnifications from the sample central region.

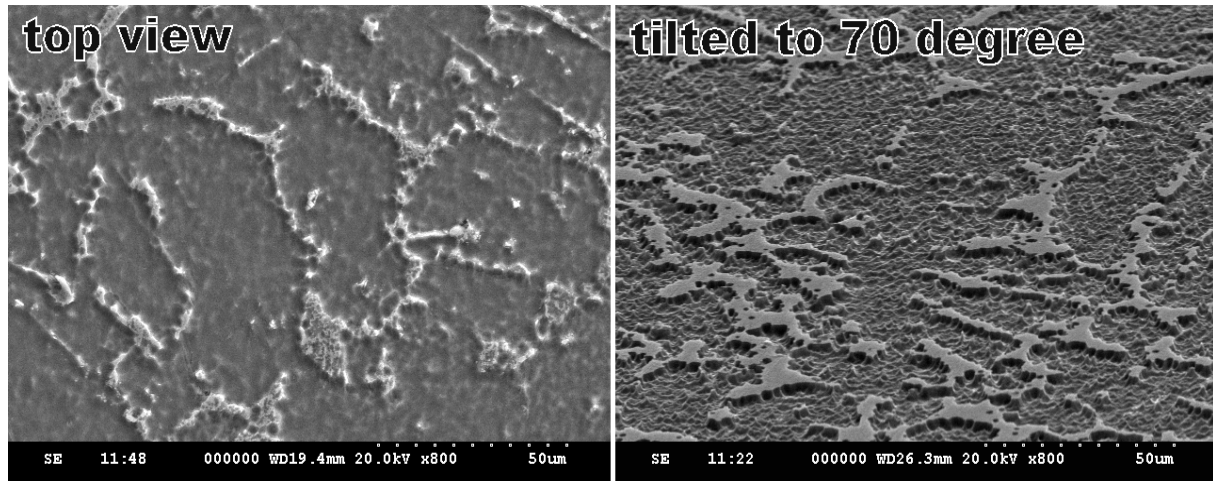


A representative EBSD scan from one grain boundary (GB) area is shown in the below, where two grains are close to Al [-111] and [011] orientations.



Only a tiny problem is grain boundary is not as smooth as inside grains, which caused a little bit EBSD indexing uncertain around GBs.

Since EBSD analysis is configured at 70 degree, an unsmooth sample surface will cause serious EBSD background subtraction problem then result uncertain EBSD indexing. One example of such effect is performed from the same unsmooth edge region as shown in the below SEM micrographs with magnification at x800.



The corresponding EBSD test is shown in the below figure. Even though EBSD pattern could still be obtained from the relevant smooth region, the unsmooth part contributed a black uncertain background, i.e. the large area EBSD scan could not be carried out from such a region.

